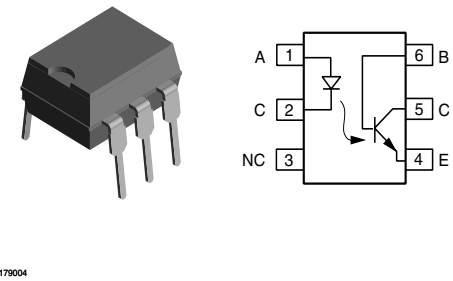
Optocoupler, Phototransistor Output, With Base Connection

Features

- Interfaces with common logic families
- Input-output coupling capacitance < 0.5 pF
- Industry Standard Dual-in line 6-pin package
- 5300 V_{RMS} isolation test voltage



i179004

Agency Approvals

- UL File #E52744 System Code H or J
- CSA 93751
- BSI IEC60950 IEC60965

- DIN EN 60747-5-2(VDE0884)
  DIN EN 60747-5-5 pending
  Available with Option 1
- FIMKO

Applications

AC mains detection

Reed relay driving

Switch mode power supply feedback

Telephone ring detection

Logic ground isolation

Logic coupling with high frequency noise rejection

Description

The H11Ax family is an Industry Standard Single Channel Phototransistor Coupler. It includes the H11A1/ H11A2/ H11A3/ H11A4/ H11A5 couplers.

Each optocoupler consists of gallium arsenide infrared LED and a silicon NPN phototransistor.

The isolation performance is accomplished through Vishay double molding isolation manufacturing process. Compliance to DIN EN 60747-5-2(VDE0884)/ DIN EN 60747-5-5 pending partial discharge isolation specification is available is by ordering option 1.

These isolation processes and the Vishay ISO9001 quality program results in the highest isolation performance available for a commercial plastic phototransistor optocoupler.

The devices are available in lead formed configuration suitable for surface mounting and are available either on tape and reel, or in standard tube shipping containers.

Footnotes

Designing with data sheet is covered in Application Note 45.

Order Information

Part	Remarks
H11A1	CTR > 50 %, DIP-6
H11A2	CTR > 20 %, DIP-6
H11A3	CTR > 20 %, DIP-6
H11A4	CTR > 10 %, DIP-6
H11A5	CTR > 30 %, DIP-6
H11A1-X006	CTR > 50 %, DIP-6 400 mil (option 6)
H11A1-X007	CTR > 50 %, SMD-6 (option 7)
H11A1-X009	CTR > 50 %, SMD-6 (option 9)

For additional information on the available options refer to Option Information.

Absolute Maximum Ratings

T_{amb} = 25 °C, unless otherwise specified

Stresses in excess of the absolute Maximum Ratings can cause permanent damage to the device. Functional operation of the device is not implied at these or any other conditions in excess of those given in the operational sections of this document. Exposure to absolute Maximum Rating for extended periods of the time can adversely affect reliability.

Input

Parameter	Test condition	Symbol	Value	Unit
Reverse voltage		V_R	6.0	V
Forward current		I_F	60	mA
Surge current	t ≤ 10 µs	I_{FSM}	2.5	A
Power dissipation		P_{diss}	100	mW

Output

Parameter	Test condition	Symbol	Value	Unit
Collector-emitter breakdown voltage		V_{CEO}	70	V
Emitter-base breakdown voltage		V_{EBO}	7.0	V
Collector current		I_C	50	mA
	(t < 1.0 ms)	I_C	100	mA
Power dissipation		P_{diss}	150	mW

Coupler

Parameter	Test condition	Symbol	Value	Unit
Isolation test voltage		V_{ISO}	5300	V_{RMS}
Creepage			≥ 7.0	mm
Clearance			≥ 7.0	mm
Isolation thickness between emitter and detector			≥ 0.4	mm
Comparative tracking index per DIN IEC 112/VDE0303,part 1			175	
Isolation resistance	V_{IO} = 500 V, T_{amb} = 25 °C	R_{IO}	10^{12}	Ω
	V_{IO} = 500 V, T_{amb} = 100 °C	R_{IO}	10^{11}	Ω
Storage temperature		T_{amb}	- 55 to + 150	°C
Operating temperature		T_{stg}	- 55 to + 100	°C
Junction temperature		T_j	100	°C
Soldering temperature	max. 10 s dip soldering: distance to seating plane ≥ 1.5 mm	T_{sld}	260	°C

Electrical Characteristics

T_{amb} = 25 °C, unless otherwise specified
Minimum and maximum values are testing requirements. Typical values are characteristics of the device and are the result of engineering evaluation. Typical values are for information only and are not part of the testing requirements.

Input

Parameter	Test condition	Part	Symbol	Min	Typ.	Max	Unit
Forward voltage	I_F = 10 mA	H11A1	V_F		1.1	1.5	V
		H11A2	V_F		1.1	1.5	V
		H11A3	V_F		1.1	1.5	V
		H11A4	V_F		1.1	1.5	V
		H11A5	V_F		1.1	1.7	V
Reverse current	V_R = 3.0 V		I_R			10	µA
Capacitance	V_R = 0, f = 1.0 MHz		C_O		50		pF

Output

Parameter	Test condition	Symbol	Min	Typ.	Max	Unit
Collector-emitter breakdown voltage	I_C = 1.0 mA, I_F = 0 mA	BV_{CEO}	30			V
Emitter-collector breakdown voltage	I_E = 100 µA, I_F = 0 mA	BV_{ECO}	7.0			V
Collector-base breakdown voltage	I_C = 10 µA, I_F = 0 mA	BV_{CBO}	70			V
Collector-emitter leakage current	V_{CE} = 10 V, I_F = 0 mA	I_{CEO}		5.0	50	nA
Collector-emitter capacitance	V_{CE} = 0	C_{CE}		6.0		pF

Coupler

Parameter	Test condition	Symbol	Min	Typ.	Max	Unit
Saturation voltage, collector-emitter	I_{CE} = 0.5 mA, I_F = 10 mA	V_{CEsat}			0.4	V
Capacitance (input-output)		C_{IO}		0.5		pF

Current Transfer Ratio

Parameter	Test condition	Part	Symbol	Min	Typ.	Max	Unit
DC Current Transfer Ratio	V_{CE} = 10 V, I_F = 10 mA	H11A1	CTR_{DC}	50			%
		H11A2	CTR_{DC}	20			%
		H11A3	CTR_{DC}	20			%
		H11A4	CTR_{DC}	10			%
		H11A5	CTR_{DC}	30			%

Switching Characteristics

Parameter	Test condition	Symbol	Min	Typ.	Max	Unit
Switching time	I_C = 2 mA, R_L = 100 Ω, V_{CE} = 10 V	t_{on}, t_{off}		3.0		µs

Typical Characteristics (T_{amb} = 25 °C unless otherwise specified)

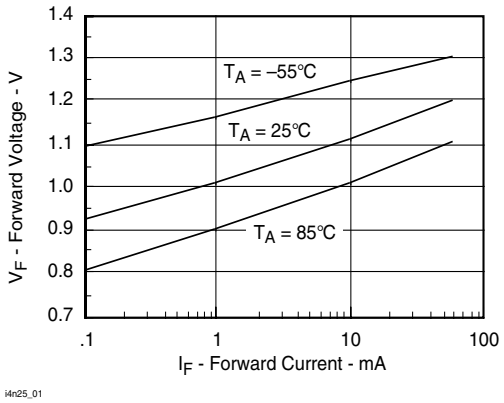


Fig. 1 Forward Voltage vs. Forward Current

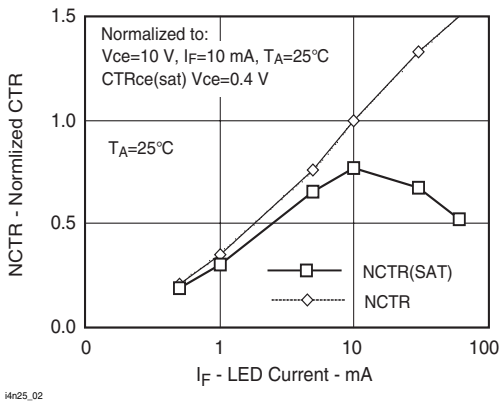


Fig. 2 Normalized Non-Saturated and Saturated CTR vs. LED Current

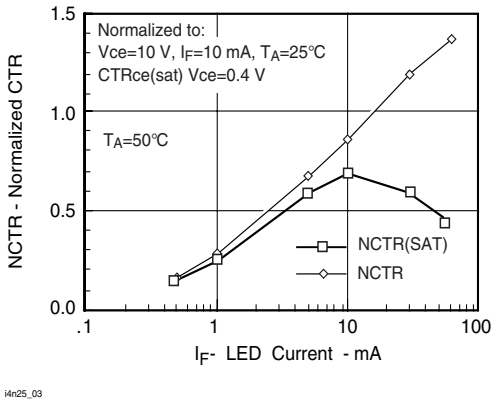


Fig. 3 Normalized Non-saturated and Saturated CTR vs. LED Current

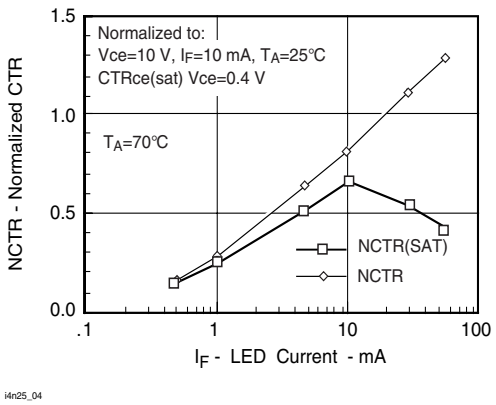


Fig. 4 Normalized Non-saturated and saturated CTR vs. LED Current

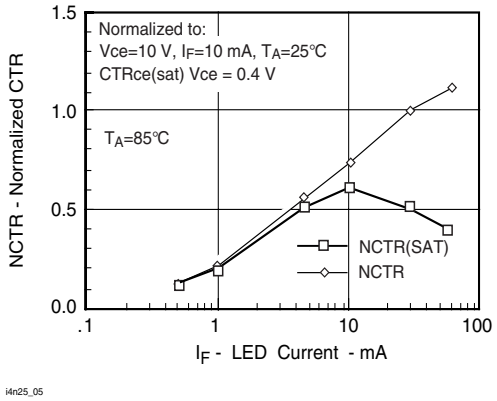


Fig. 5 Normalized Non-saturated and saturated CTR vs. LED Current

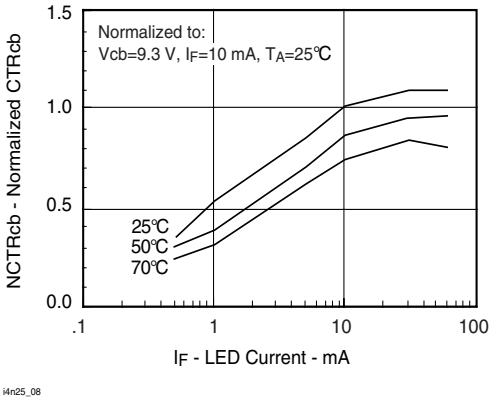


Fig. 8 Normalized CTRcb vs. LED Current and Temp.

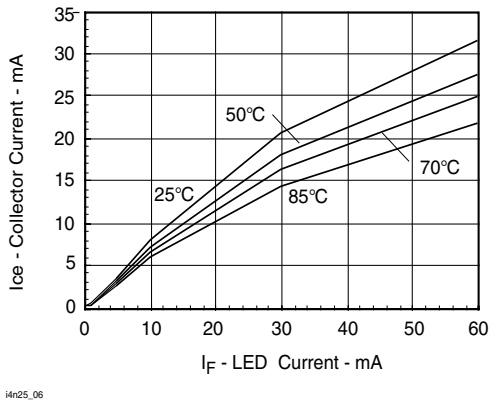


Fig. 6 Collector-Emitter Current vs. Temperature and LED Current

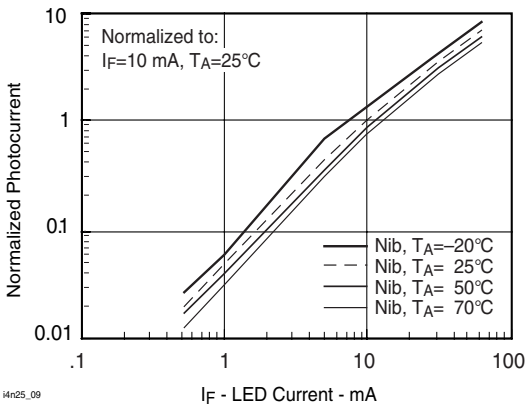


Fig. 9 Normalized Photocurrent vs. I_F and Temp.

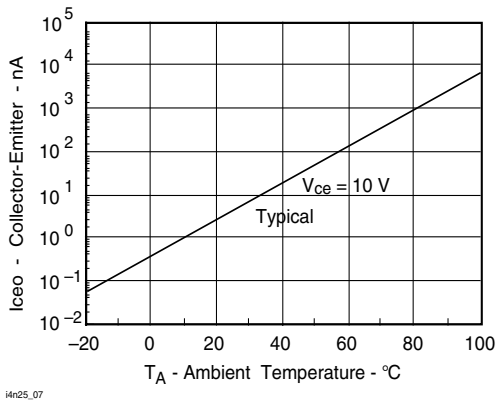


Fig. 7 Collector-Emitter Leakage Current vs.Temp.

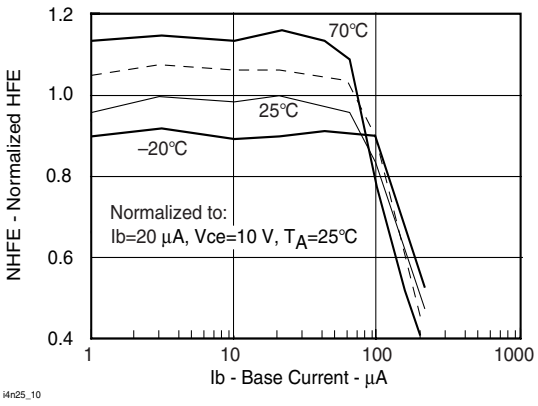


Fig. 10 Normalized Non-saturated HFE vs. Base Current and Temperature

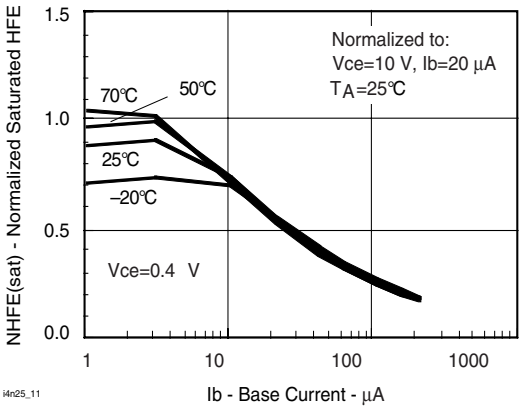


Fig. 11 Normalized HFE vs. Base Current and Temp.

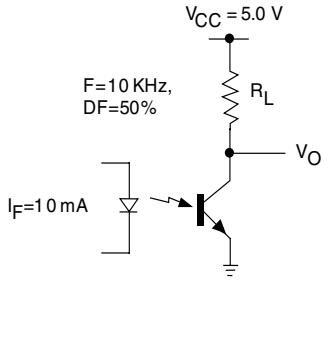


Fig. 14 Switching Schematic

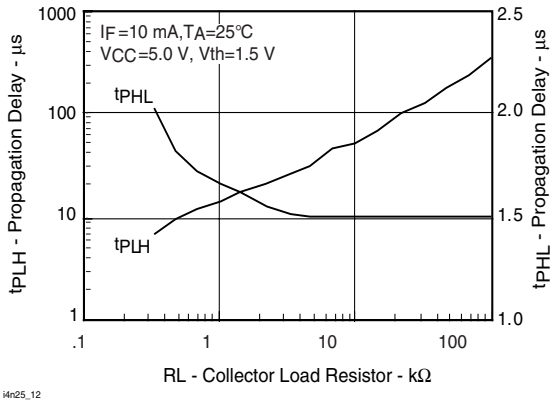


Fig. 12 Propagation Delay vs. Collector Load Resistor

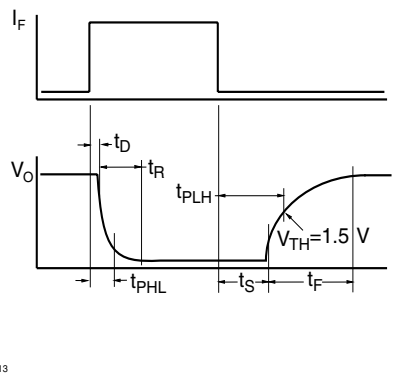
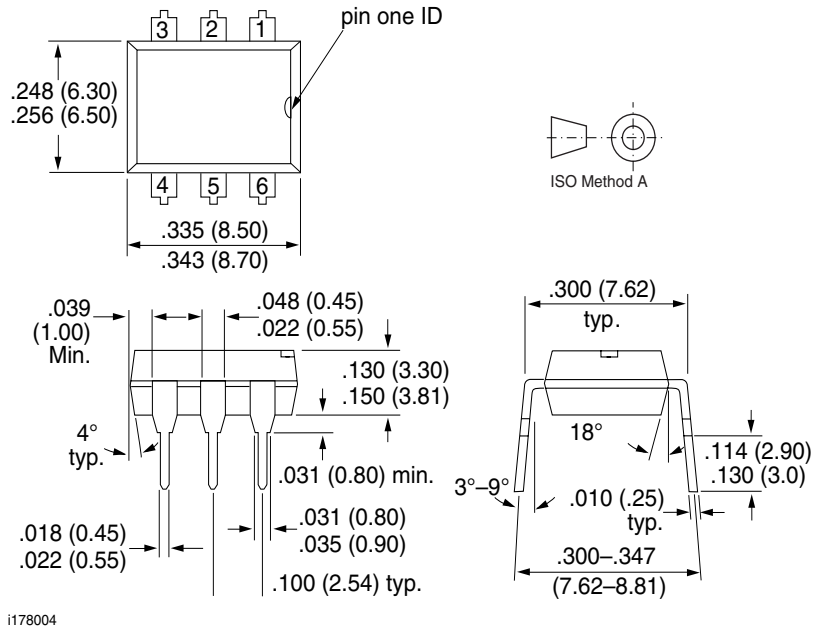
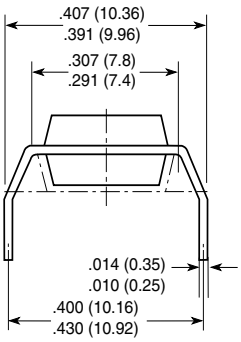


Fig. 13 Switching Timing

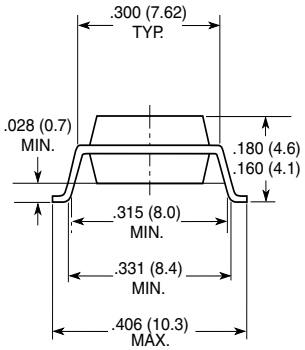
Package Dimensions in Inches (mm)



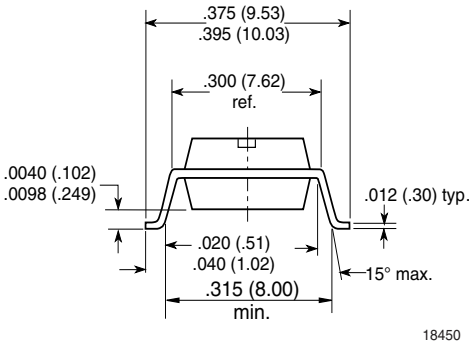
Option 6



Option 7



Option 9



Ozone Depleting Substances Policy Statement

It is the policy of **Vishay Semiconductor GmbH** to

1. Meet all present and future national and international statutory requirements.
2. Regularly and continuously improve the performance of our products, processes, distribution and operatingsystems with respect to their impact on the health and safety of our employees and the public, as well as their impact on the environment.

It is particular concern to control or eliminate releases of those substances into the atmosphere which are known as ozone depleting substances (ODSs).

The Montreal Protocol (1987) and its London Amendments (1990) intend to severely restrict the use of ODSs and forbid their use within the next ten years. Various national and international initiatives are pressing for an earlier ban on these substances.

Vishay Semiconductor GmbH has been able to use its policy of continuous improvements to eliminate the use of ODSs listed in the following documents.

1. Annex A, B and list of transitional substances of the Montreal Protocol and the London Amendments respectively
2. Class I and II ozone depleting substances in the Clean Air Act Amendments of 1990 by the Environmental Protection Agency (EPA) in the USA
3. Council Decision 88/540/EEC and 91/690/EEC Annex A, B and C (transitional substances) respectively.

Vishay Semiconductor GmbH can certify that our semiconductors are not manufactured with ozone depleting substances and do not contain such substances.

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